Key: IEEE JNL = IEEE Journal or Magazine, IEE JNL = IEE Journal or Magazine, IEEE CNF = IEEE Conference, IEE CNF = IEE Conference, IEEE STD = IEEE Standard

1. **Comprehensive CAD support for boundary scan implementation in ASICs**
   Lestrat, P.; Leveugle, R.; Magarshack, P.;
   Euro ASIC '91
   27-31 May 1991 Page(s):278 - 283
   IEEE CNF

2. **Tradeoff decisions made for a P1149.1 controller design [ATE]**
   Vining, S.;
   Test Conference, 1989. Proceedings. 'Meeting the Tests of Time'., International
   29-31 Aug. 1989 Page(s):47 - 54
   IEEE CNF

3. **A simulation-based protocol-driven scan test design rule checker**
   Pitty, E.B.; Martin, D.; Ma, H.-K.T.;
   Test Conference, 1994. Proceedings., International
   2-6 Oct. 1994 Page(s):999 - 1006
   IEEE CNF

4. **A unifying methodology for intellectual property and custom logic testing**
   Bhatia, S.; Gheewala, T.; Varma, P.;
   Test Conference, 1996. Proceedings., International
   20-25 Oct. 1996 Page(s):639 - 648
   IEEE CNF

5. **A heuristic algorithm for the minimization of test application time in digital circuits with boundary-scan capabilities**
   Evans, A.H.; Macii, E.;
   Electrotechnical Conference, 1996. MELECON '96., 8th Mediterranean
   Volume 1, 13-16 May 1996 Page(s):473 - 475 vol.1
   IEEE CNF

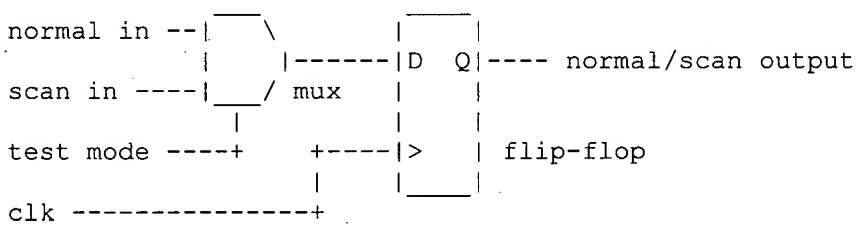
6. **Distributed probabilistic diagnosis of MCMs on large area substrates**
   Sasidhar, K.; Chatterjee, A.; Agarwal, V.K.; Hughes, J.;
   Test Conference, 1995. Proceedings., International
   21-25 Oct. 1995 Page(s):208 - 216
   IEEE CNF

7. **Observing test response of embedded cores through surrounding logic**
   Jaini, P.K.; Touba, N.A.;
   Circuits and Systems, 1999. ISCAS '99. Proceedings of the 1999 IEEE International Symposium on
   Volume 1, 30 May-2 June 1999 Page(s):119 - 123 vol.1
   IEEE CNF

scan register

(circuit design) A digital logic circuit which can act either as a flip-flop or as a serial shift register and which is used to form a scan path.

The most common design is a multiplexed flip-flop:



The addition of a multiplexor (mux) to each flip-flop's input allows operation in either normal or test mode. The output of each flip-flop goes to the normal functional logic as well as to the scan input of the next multiplexor in the scan path.

The other common design is level-sensitive scan design (LSSD).

(1995-02-14)

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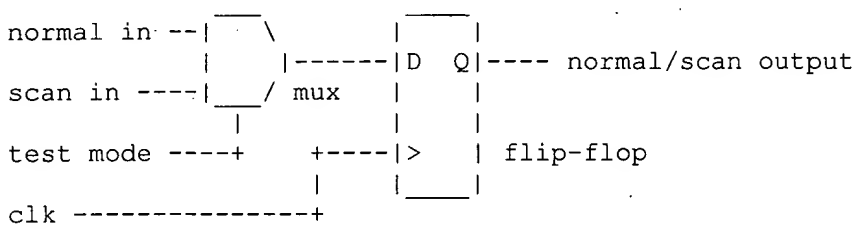

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Nearby terms: scanner « scanno « scan path « **scan register** » SCC » SCCS » SCEPTRE

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
L1	4255	(differential with input with buffer)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/07/06 19:37
L2	39	(differential with input with buffer) and (scan with (test testing))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/07/06 19:37
S1	204	seamless adj data	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/02/22 15:07
S2	49	("6556037" "5631912" "6163864" "5872796" "5892778" "6122762" "6219812" "6219812" "5598421" "5949701" "6073254" "6314539" "6499124" "6539520" "5465259" "5841792" "5898704" "6195775" "5781560" "5928374" "4975640" "5321641" "5341096" "5677916" "5701309" "5448575" "5736849" "5042034" "5299136" "5500862" "6076178" "6321355" "6324096" "6343365" "6353905" "6370665" "6442092" "6519728" "5640404" "6000050" "6449755" "6324614" "6408413" "5357572" "5936423" "5968195" "5648973" "6158034" "5935266" "6594802").pn.	US-PGPUB; USPAT	OR	ON	2005/07/06 19:36
S3	11	"891310"	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/02/21 12:14

East shut down + Majority of search did not back up

CB

S4	30	(("6556037" "5631912" "6163864" "5872796" "5892778" "6122762" "6219812" "6219812" "5598421" "5949701" "6073254" "6314539" "6499124" "6539520" "5465259" "5841792" "5898704" "6195775" "5781560" "5928374" "4975640" "5321641" "5341096" "5677916" "5701309" "5448575" "5736849" "5042034" "5299136" "5500862" "6076178" "6321355" "6324096" "6343365" "6353905" "6370665" "6442092" "6519728" "5640404" "6000050" "6449755" "6324614" "6408413" "5357572" "5936423" "5968195" "5648973" "6158034" "5935266" "6594802").pn.) and serial and parallel	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/02/21 13:00
S5	17	(("6556037" "5631912" "6163864" "5872796" "5892778" "6122762" "6219812" "6219812" "5598421" "5949701" "6073254" "6314539" "6499124" "6539520" "5465259" "5841792" "5898704" "6195775" "5781560" "5928374" "4975640" "5321641" "5341096" "5677916" "5701309" "5448575" "5736849" "5042034" "5299136" "5500862" "6076178" "6321355" "6324096" "6343365" "6353905" "6370665" "6442092" "6519728" "5640404" "6000050" "6449755" "6324614" "6408413" "5357572" "5936423" "5968195" "5648973" "6158034" "5935266" "6594802").pn.) and serial and parallel and buffer	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/02/21 13:43
S6	33153	input adj buffer	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/02/21 14:26
S7	8241	(input adj buffer) and (input adj terminal)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/02/21 14:27
S8	578	(input adj buffer) and (input adj terminal) and ((serial with parallel) with (convert conversion converting change changing changed converted))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/02/21 14:29

S9	144	(input adj buffer) and (input adj terminal) and ((serial with parallel) with (convert conversion converting change changing changed converted)) and scan	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/02/21 14:29
S10	39	(input adj buffer) and (input adj terminal) and ((serial with parallel) with (convert conversion converting change changing changed converted)) and (scan with (test boundary chan latch))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/02/21 15:04
S11	184	input same buffer same parallel same serial same scan	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/02/21 15:05
S12	56	(input same buffer same (parallel near serial) same scan)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/02/21 15:28
S13	119733	(multiple several plurality parallel) near2 input	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/02/21 15:31
S14	0	((multiple several plurality parallel) near2 input) and bouandry adj scan	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/02/21 15:32
S15	897	((multiple several plurality parallel) near2 input) and boundary adj scan	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/02/21 15:32
S16	15959	((multiple several plurality parallel) near2 input) and ((boundary adj scan) or (scan))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/02/21 15:33
S17	1944	((multiple several plurality parallel) near2 input) and ((boundary adj scan) or (scan)) and (parallel near serial)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/02/21 15:33
S18	320	((multiple several plurality parallel) near2 input) and ((boundary adj scan) or (scan)) same (parallel near serial)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/02/21 15:36

S19	707578	buffer	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/11/29 16:03
S20	19073	buffer and (serial near2 parallel)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/11/29 16:04
S21	7921	buffer and ((serial near2 parallel) with (output input))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/11/29 16:05
S22	7921	buffer and ((serial near2 parallel) with (output input)) and (serial near2 parallel)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/11/29 16:05
S23	2200	buffer and ((serial near2 parallel) with (output input)) and (serial near2 parallel) and scan	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/11/29 16:06
S24	1744	buffer and ((serial near2 parallel) with (output input)) and (serial near2 parallel) and scan and (mux multiplexer multiplexor selector selectively)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/11/29 16:10
S25	604	buffer and ((serial near2 parallel) with (output input)) and (serial near2 parallel) and scan and (mux multiplexer multiplexor selector selectively) and ((mux multiplexer multiplexor selector selectively) with buffer)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/11/29 16:11
S26	253	buffer and ((serial near2 parallel) with (output input)) and (serial near2 parallel) and (scan with (path register boundary test)) and (mux multiplexer multiplexor selector selectively) and ((mux multiplexer multiplexor selector selectively) with buffer)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/11/29 16:13
S27	2	"6530045" .pn.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/12/02 13:00

S28	1577	redundant adj column	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/12/02 13:01
S29	956	redundant adj column	USPAT	OR	ON	2004/12/02 13:01
S30	826	(redundant adj column) and replac$	USPAT	OR	ON	2004/12/02 13:01
S31	381	(redundant adj column) and replac$ and repair	USPAT	OR	ON	2004/12/02 15:33
S32	4	"5581566".pn. "5793770".pn.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/12/02 15:53
S33	0	"042577"	EPO; DERWENT	OR	ON	2004/12/02 15:55
S34	0	"004476"	EPO; DERWENT	OR	ON	2004/12/02 15:55